

Claims

What is claimed is:

- Sub C*
- Sub 2*
1. An electronic device power testing method, comprising steps of:
 - (a) applying a nominal voltage to an electronic component;
 - (b) introducing a voltage disruption to the nominal voltage;
 - (c) repeating the voltage disruption for a specified number of instances.
 2. The method of claim 1 wherein introducing a voltage disruption comprises applying an increase in voltage.
 3. The method of claim 1 wherein introducing a voltage disruption comprises applying a decrease in voltage.
 4. The method of claim 1 wherein step (d), prior to step (a), comprises applying a sequence of voltages during power-on, wherein a second voltage is activated a specific amount of time after a first voltage was activated.
 5. The method of claim 1 wherein step (d) comprises applying a sequence of voltages during power-off, wherein a second voltage is deactivated a specific amount of time after a first voltage was deactivated.

cont.
or 2

6. The method of claim 1 wherein step (d), prior to step (b), comprises adjusting a combination of variables selected from the group consisting of voltage disruption frequency, voltage disruption time duration and voltage disruption magnitude.

Sub 3

7. The method of claim 6 wherein computer software controls the adjusting of selected variables.

Sub 3

8. An electronic device power tester, comprising:

- (a) at least one power source;
- (b) circuitry coupled to a power source, the circuitry being configured to produce a voltage disturbance; and
- (c) a connector linked from the circuitry to a device.

Sub 5

9. The power tester of claim 8 wherein the voltage disturbance is an increase in voltage.

10. The power tester of claim 8 wherein the voltage disturbance is a decrease in voltage.

11. The power tester of claim 8 wherein there are multiple power sources that comprise multiple voltage magnitudes.

12. The power tester of claim 11 wherein the circuitry is configured to produce both a decrease and an increase in voltage.

Sub 1

13. The power tester of claim 12 wherein there are two connectors linked from the circuitry to two separate devices, one connector configured for the

voltage disturbances that are due to an increase in voltage and the other connector configured for the voltage disturbances that are due to a decrease in voltage.

- Sub C7*
- ~~14. The power tester of claim 12 wherein a computer is connected to the power tester and is programmed to allow an operator to specify certain operating parameters of the power tester, including number of voltage disturbances, voltage disruption frequency, voltage disruption time duration, and voltage disruption magnitude.~~
- ~~15. The power tester of claim 11 wherein the circuitry is configured to provide a power on sequence where a first voltage is activated and then, after a specific amount of time from when the first voltage was activated, a second voltage is activated.~~
- ~~16. The power tester of claim 11 wherein the circuitry is configured to provide a power off sequence where a first voltage is deactivated and then, after a specific amount of time from when the first voltage was deactivated, a second voltage is deactivated.~~
- ~~17. An electronic device power tester comprising:
at least one power source;
a connector to connect an electronic device to the power tester; and
means for generating a voltage disturbance to be delivered to the device via the connector.~~